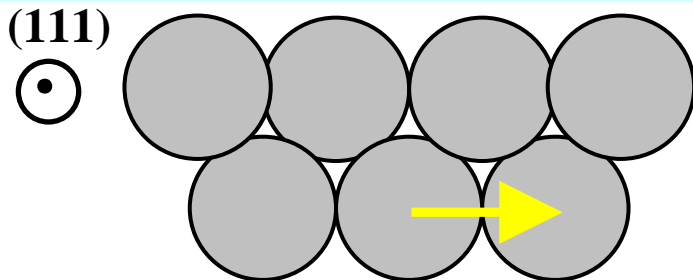
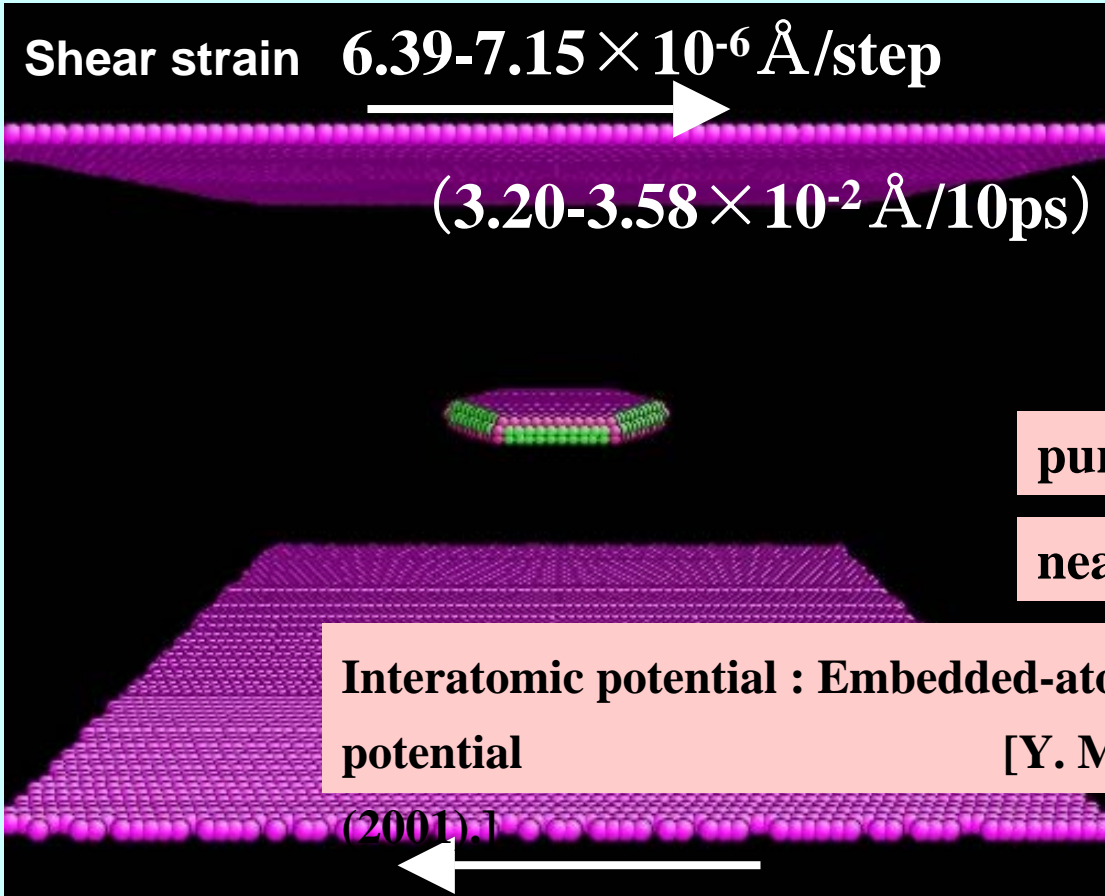


Molecular dynamics study on radiation hardening and fracture processes in FCC metals

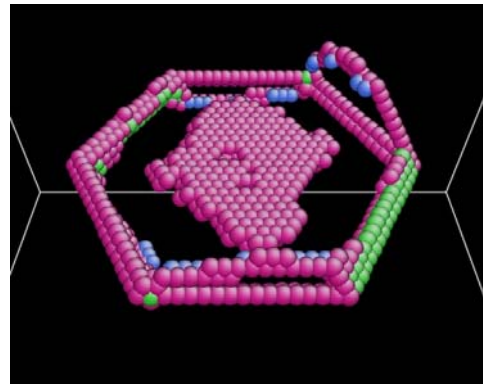
Hideo Kaburaki (JAERI)

Effect of external shear stress for unfaulinging

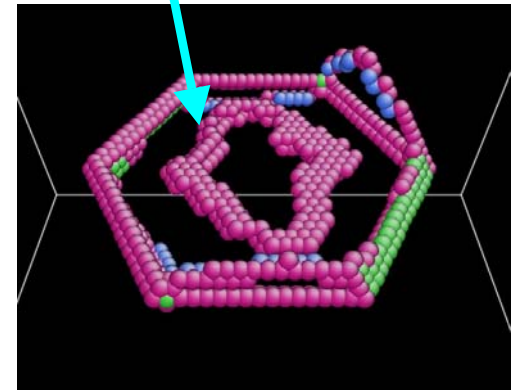


Unfaulting process of H721 vacancy loop

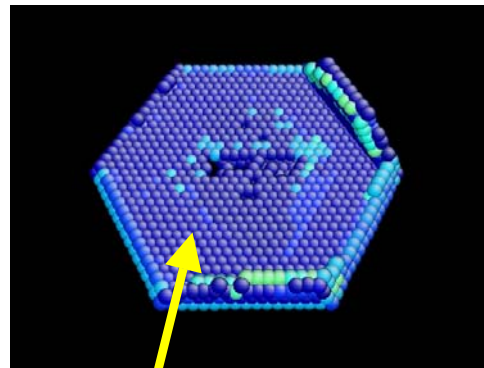
Coordination number representation



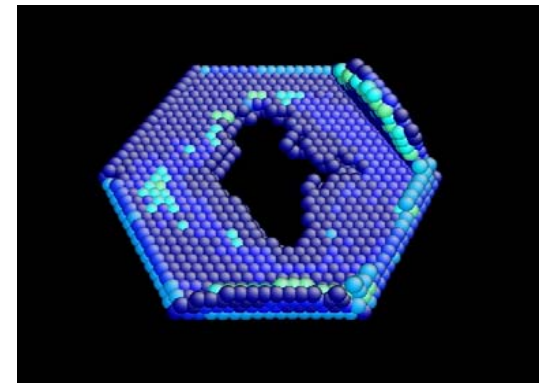
Partial dislocation loop



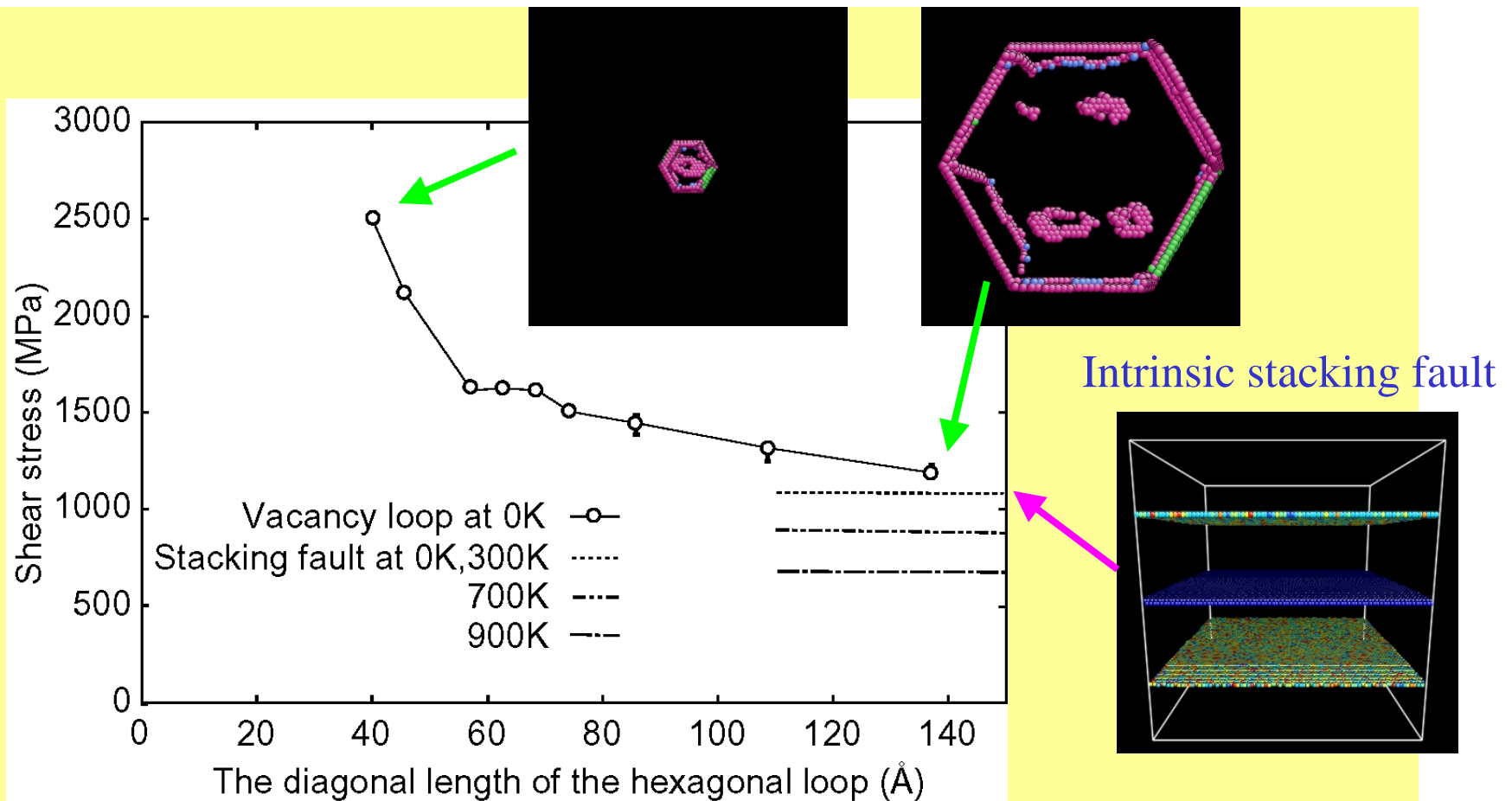
Central symmetry parameter representation



Stacking fault

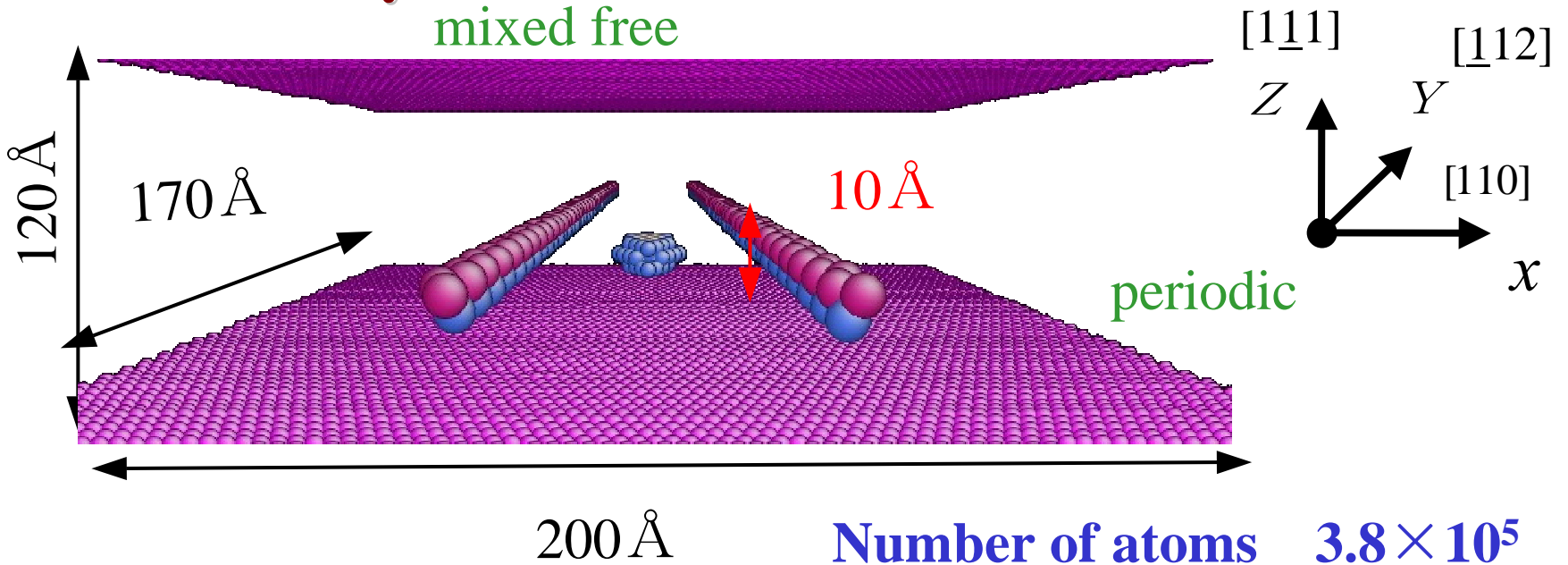


Results of unfaultering critical shear stress for vacancy loops



Hardening process --- the interaction of an edge dislocation with a hexagonal interstitial dislocation loop

Simulation System



Interatomic potential : Embedded-atom method (EAM)

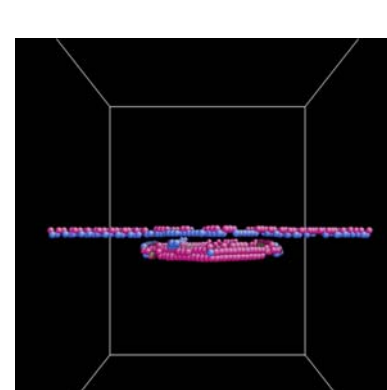
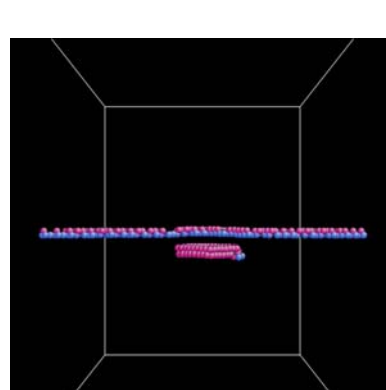
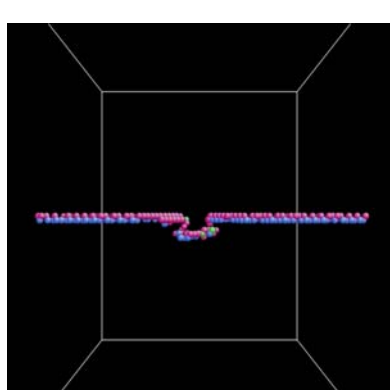
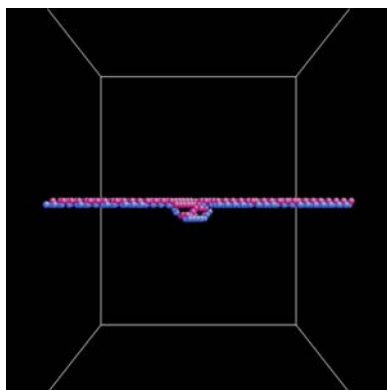
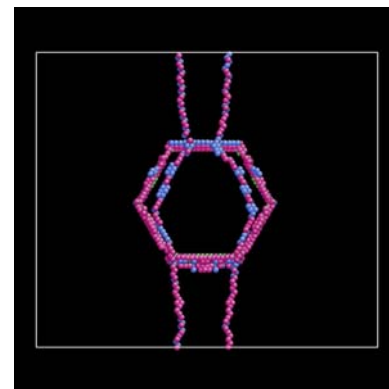
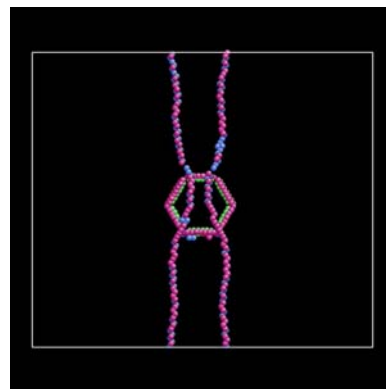
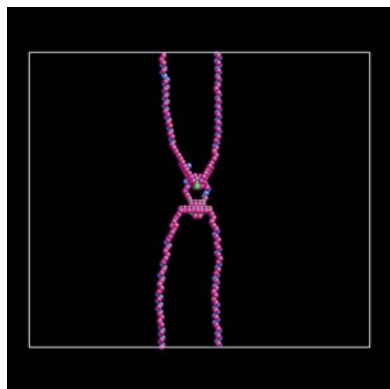
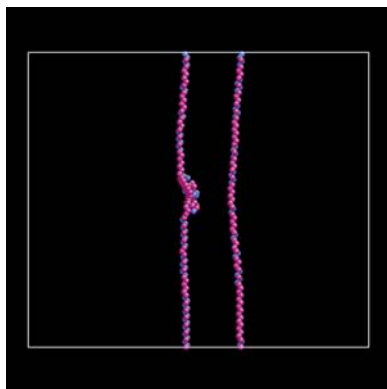
potential **Cu, Al**

[Y. Mishin *et al.*, *PRB* (2001).]

$$E_{tot} = \frac{1}{2} \sum_{ij} V(r_{ij}) + \sum_i F(\bar{\rho}_i)$$

V : Pair potential
 F : Embedding energy

Pinning structure formed due to the interaction of an edge dislocation and an interstitial cluster in **Cu**



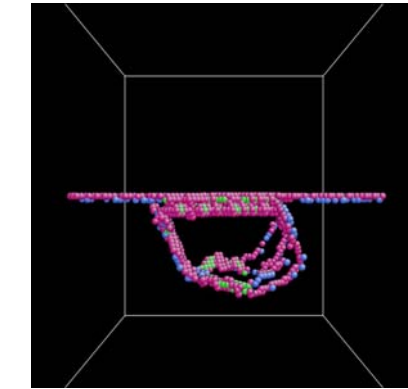
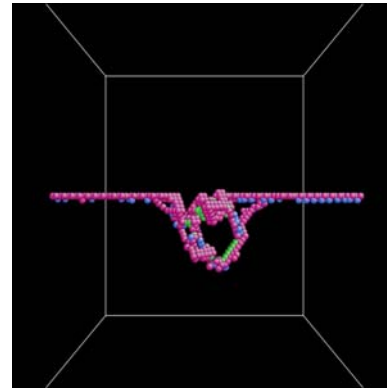
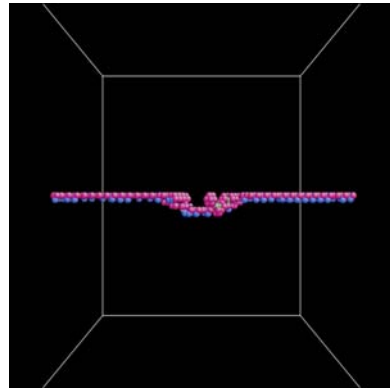
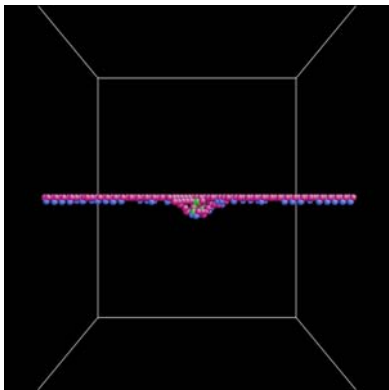
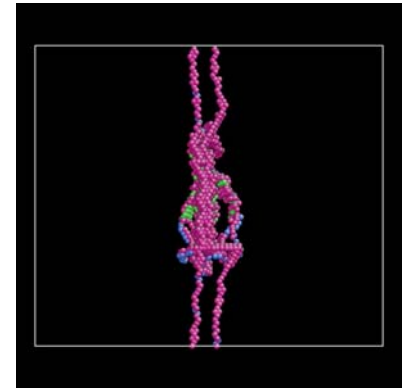
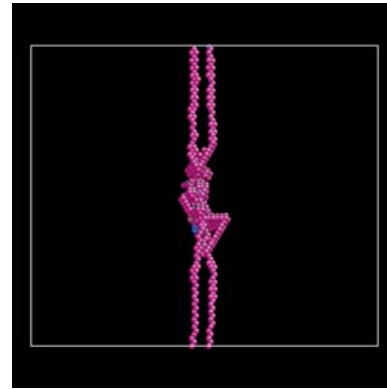
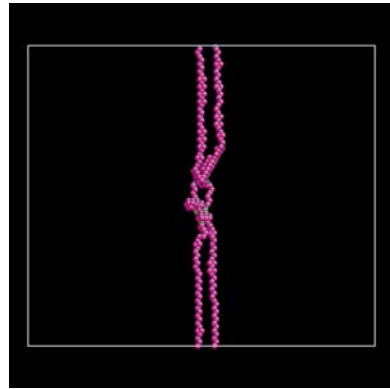
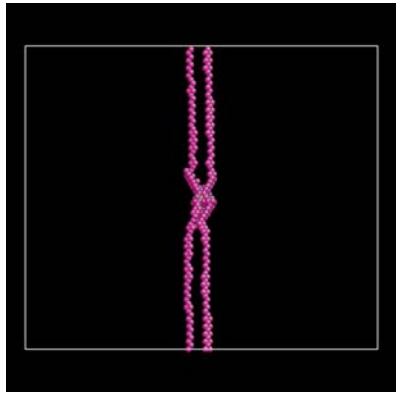
H007

H037

H169

H721

Pinning structure formed due to the interaction of an edge dislocation and an interstitial cluster in Al



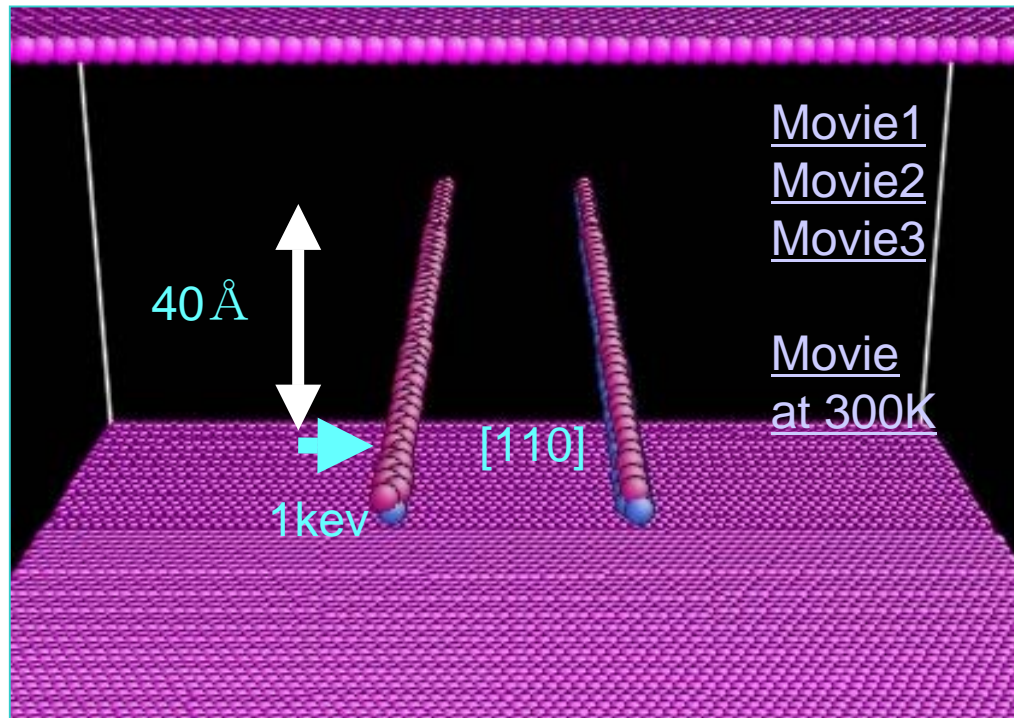
H007

H037

H169

H721

A molecular dynamics study on displacement cascades in the strain field of an edge dislocation in Cu

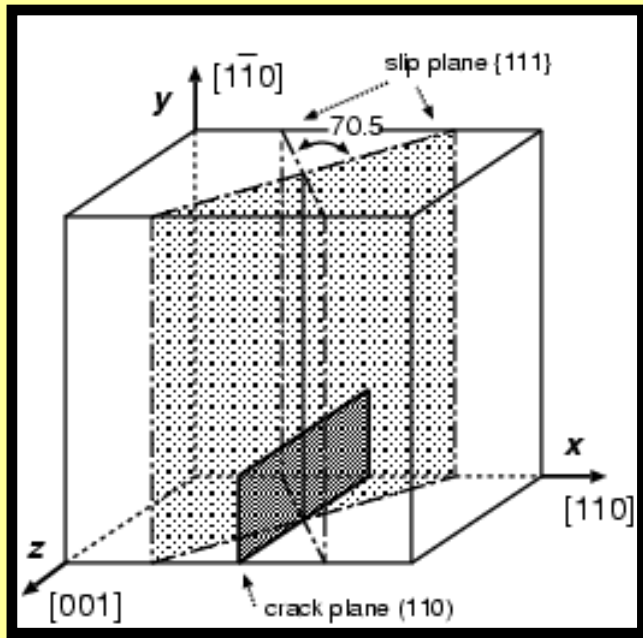


$205 \times 177 \times 125 \text{ \AA}$

Fracture process --- development of crack-tip microstructures

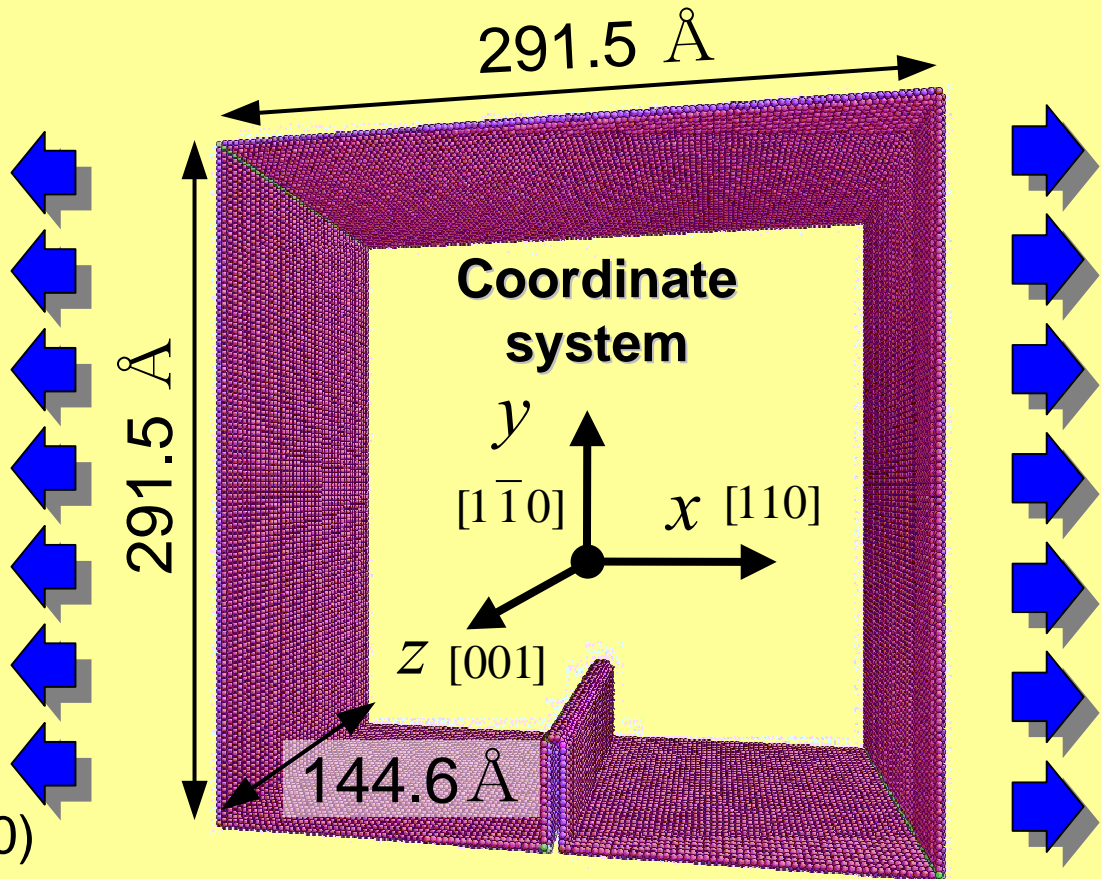
Mode I crack in a single fcc crystal

Simulation Cell



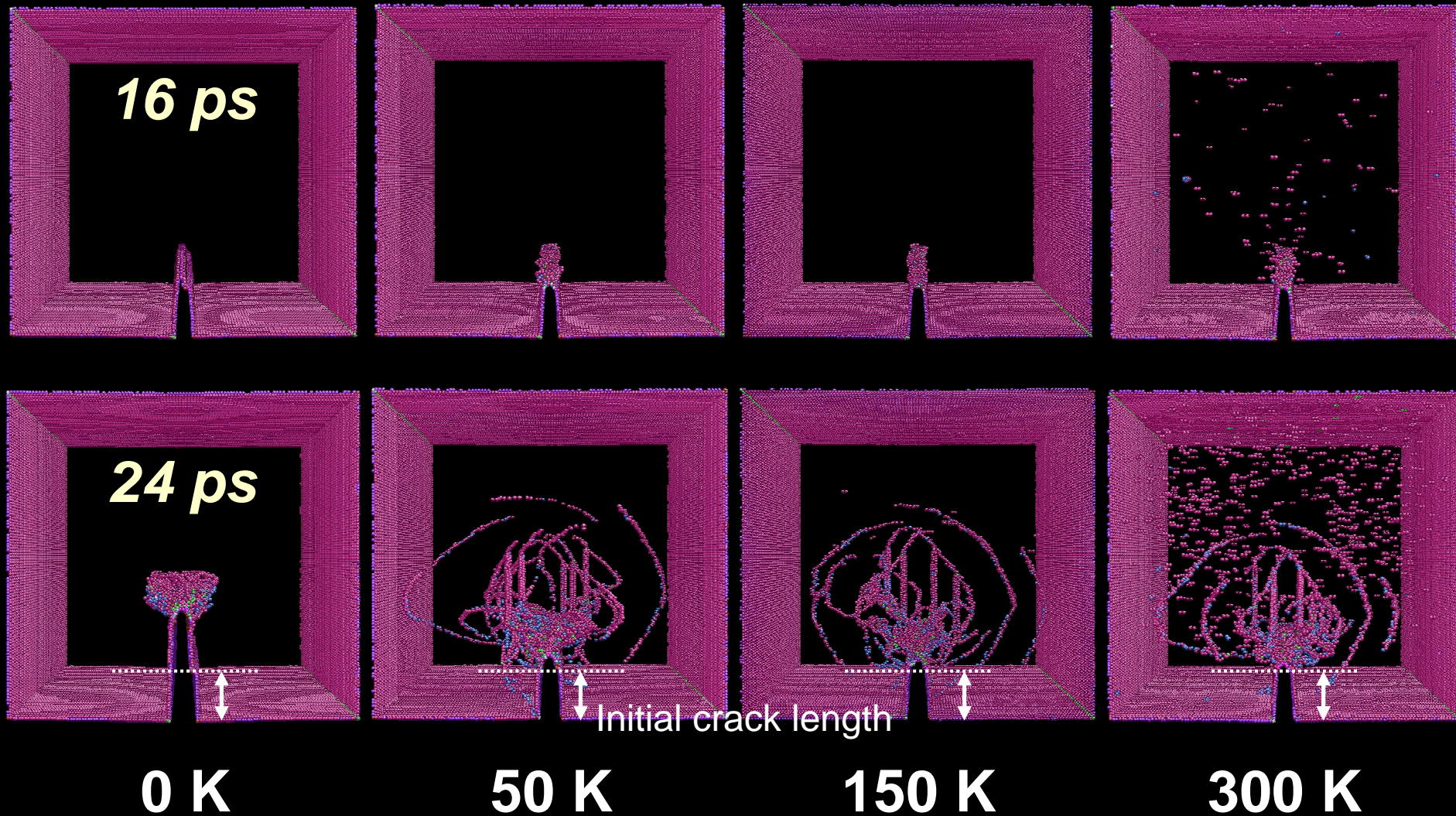
Slip plane = $\{111\}$

The slip planes and the (110) crack plane intersect obliquely at $70.5^\circ \times \frac{1}{2}$

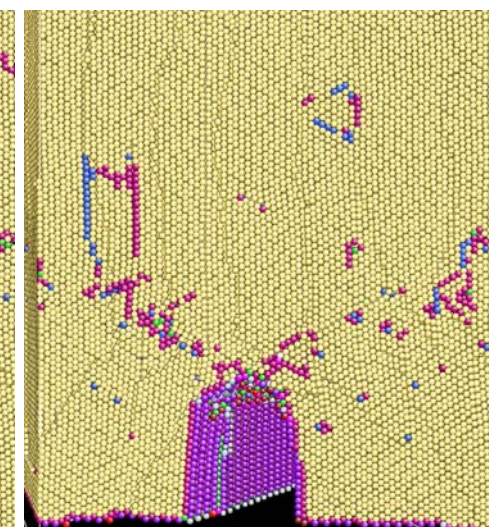
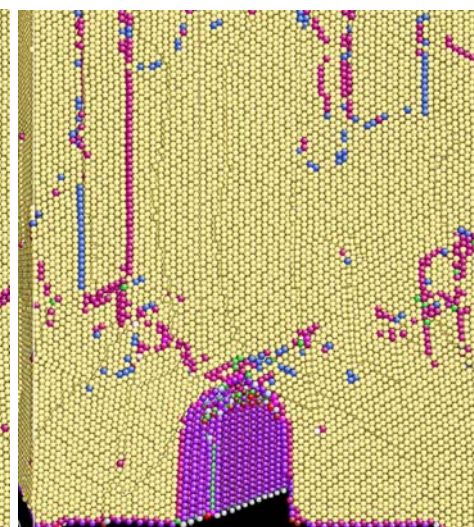
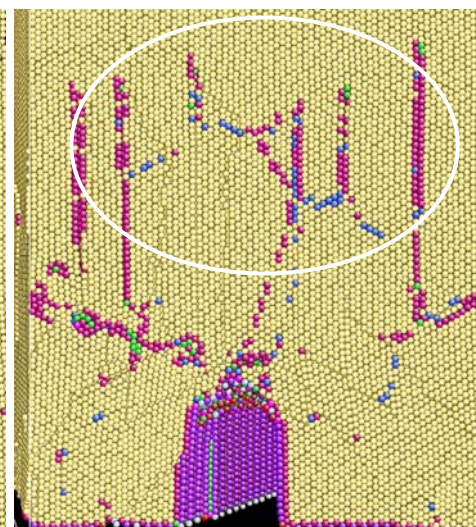
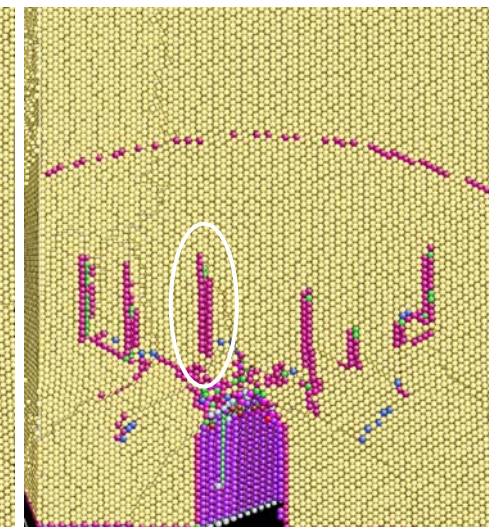
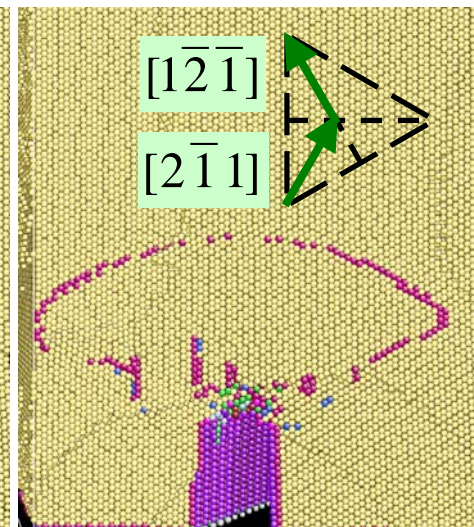
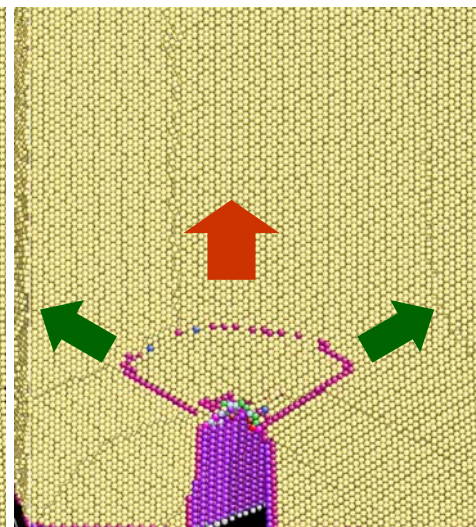
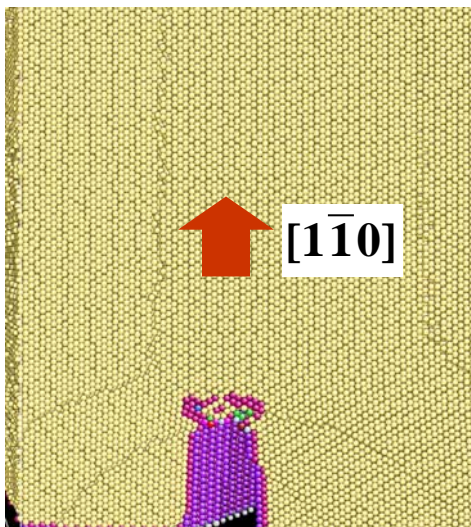


of atoms : 1,036,960

Temperature dependence on the crack-tip dislocation nanostructures (Cu)



Disl. motion on the slip plane (Cu, 50K)



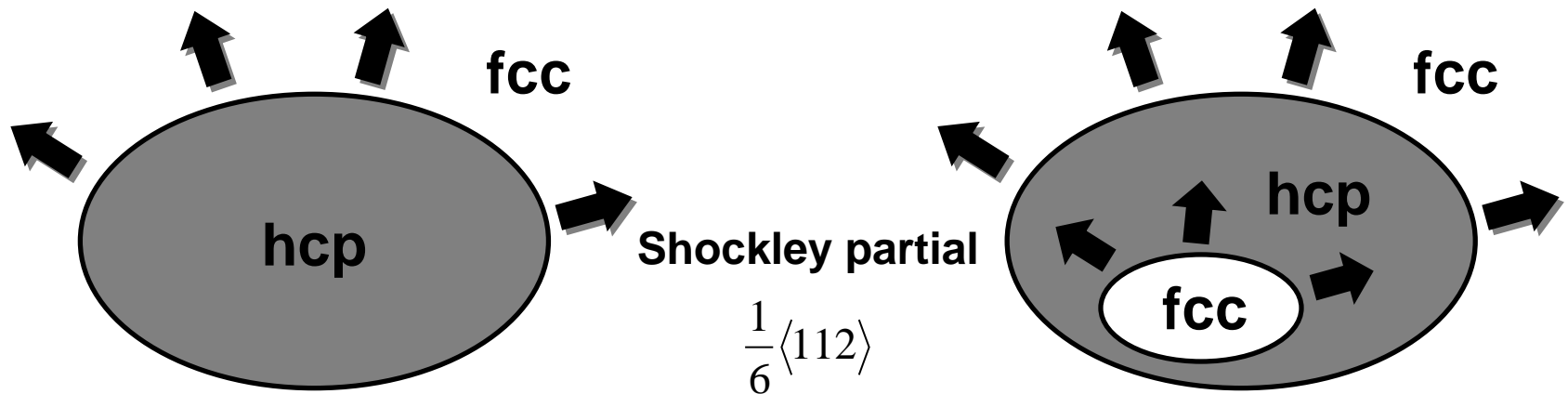
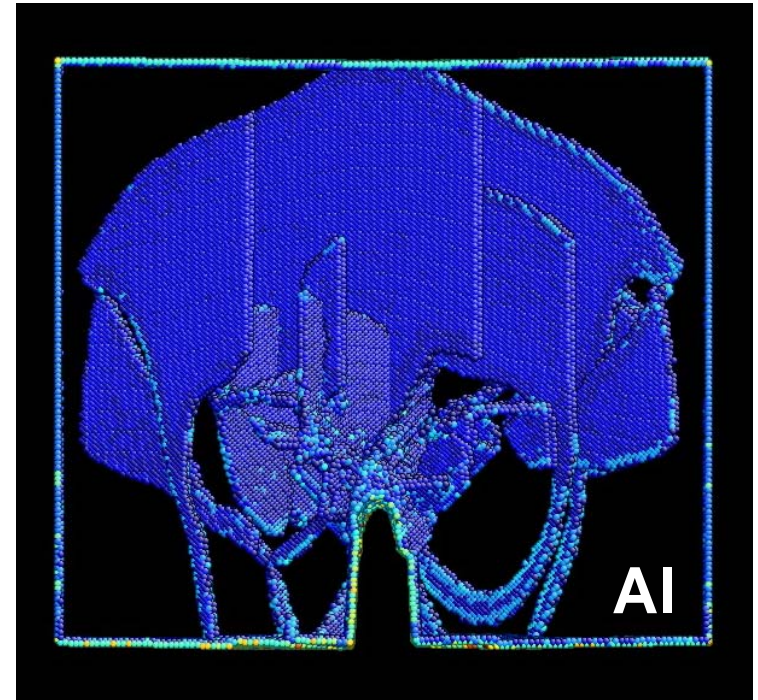
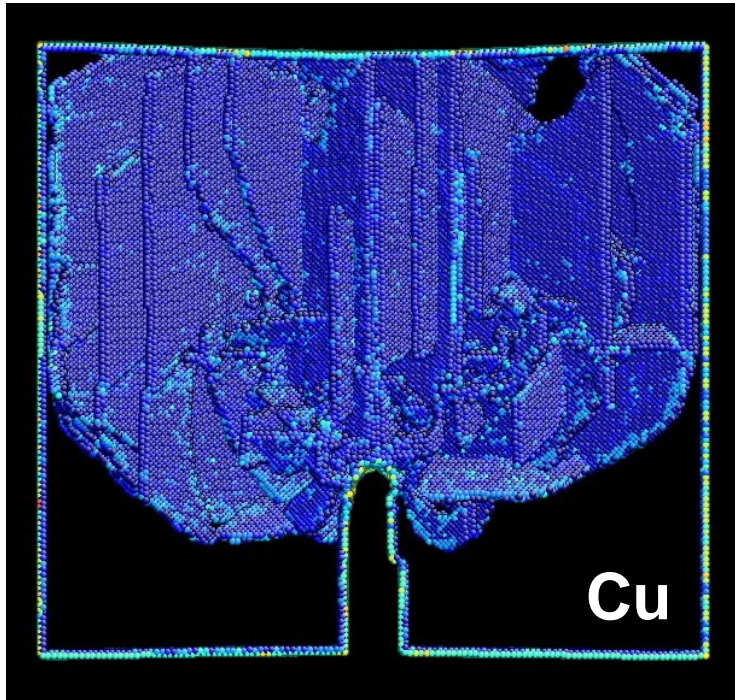
24 ps

26 ps

28 ps

30 ps

Expansion and emission process of stacking-fault loops



C.N. = 10 : Green
11 : Red
12 : omitted (f.c.c.)
13 : Blue

